

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of Applicants:

Date: October 29, 2008

Beaman et al.

Group Art Unit: 2829

Serial No.: 09/382,834

Examiner: V. P. Nguyen

Filed: August 25, 1999

Docket No.: YOR919930028US5

For: HIGH DENSITY INTEGRATED CIRCUIT APPARATUS, TEST PROBE AND
METHODS OF USE THEREOF

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

please enter

10/31/08

/VN/

RESPONSE AFTER FINAL ACTION DATED 05/04/2008 AND
ADVISORY ACTION DATED 10/14/2008

Sir:

In response to the Final Office Action dated 05/04/2008 and Advisory Action dated 10/14/2008, please consider the following.